

	Application No.	Applicant(s)	
AL	10/616,086	MILLER ET AL.	
Notice of Allowability	Examiner	Art Unit	
	Anjan K. Deb	2858	
The MAILING DATE of this communication appearance All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication IGHTS. This application is subject to	olication. If not includ will be mailed in due	ed course. THIS
1. This communication is responsive to amendment filed 05/2	<u>23/2005</u> .		
2. The allowed claim(s) is/are 1-15 and 32-46.			
3. \boxtimes The drawings filed on <u>23 May 2005</u> are accepted by the Ex	kaminer.		
4.			
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	5. ☐ Notice of Informal P 6. ☐ Interview Summary Paper No./Mail Dat 08), 7. ☐ Examiner's Amendr 8. ☑ Examiner's Stateme 9. ☐ Other	(PTO-413), e nent/Comment	·
		Anjan K Deb Primary Examiner Art Unit: 2858	

1. This office action is in response to amendment filed 05/23/2005.

Allowable Subject Matter

2. Claims 1-15, 32-46 are allowed.

Reasons for Allowance

3. The following is an examiner's statement of reasons for allowance:

The primary reason for allowance of the claims is the inclusion of determining one or more properties of the insulating film using the charge density measurement, the voltage measurement, and the rate of voltage decay, wherein the one or more properties comprise a thickness of the insulating film. The above limitations included in all of the dependent claims in combination with remaining claims limitations is neither disclosed or suggested in the prior art.

Conclusion

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Ma et al. (US 6,011,404) discloses apparatus and method comprising non-contact type measurement including measuring surface voltage, rate of voltage decay, and charge density.

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Ma et al. did not explicitly disclose obtaining a thickness of the insulating film from these measurements.

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Verkuil (US 5,498,974) disclosed apparatus and method comprising non-contact type measurement including surface voltage (column 4 lines 19-21), rate of voltage decay (measuring voltage changes), and charge density (Qmobile) but did not explicitly disclose obtaining a thickness of the insulating material from these measurements.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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Contact Information

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dr. Anjan K. Deb whose telephone number is 571-272-2228. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Lefkowitz Edwards can be reached at 571-272-2180.

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7/13/05